

MBN1800FH33F

Silicon N-channel IGBT 3300V F version

FEATURES

- * Soft switching behavior, low switching loss & low conduction loss :
 - Soft low-injection punch-through
 - Advanced Trench High conductivity IGBT.
- * Low driving power due to low input capacitance with trench MOS gate.
- * Low noise recovery: Ultra soft fast recovery diode.
- * High Current rate Package.
- * Low $R_{th(j-c)}$ & low stray inductance.
- * RoHS

ABSOLUTE MAXIMUM RATINGS ($T_C=25^\circ\text{C}$)

| Item | Symbol | Unit | MBN1800FH33F |
|---------------------------|-------------------|------------------|---------------------|
| Collector Emitter Voltage | V_{CES} | V | 3,300 |
| Gate Emitter Voltage | V_{GES} | V | ± 20 |
| Collector Current | DC | I_C | 1,800 |
| | 1ms | I_{CRM} | 3,600 |
| Forward Current | DC | I_F | 1,800 |
| | 1ms | I_{FRM} | 3,600 |
| Junction Temperature | $T_{vj\text{op}}$ | $^\circ\text{C}$ | -50 ~ +150 |
| Storage Temperature | T_{stg} | $^\circ\text{C}$ | -50 ~ +150 |
| Isolation Voltage | V_{ISO} | V_{RMS} | 10,200(AC 1 minute) |
| Screw Torque | Terminals (M4/M8) | - | 2/10 (1) |
| | Mounting (M6) | - | 6 (2) |

Notes: (1) Recommended Value $1.8\pm 0.2/9\pm 1\text{N}\cdot\text{m}$ (2) Recommended Value $5.5\pm 0.5\text{N}\cdot\text{m}$

ELECTRICAL CHARACTERISTICS

| Item | Symbol | Unit | Min. | Typ. | Max. | Test Conditions | |
|--------------------------------------|---------------|---------------|------|-------|------|--|------------------|
| Collector Emitter Cut-Off Current | I_{CES} | mA | - | - | 0.6 | $V_{CE}=3,300\text{V}, V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$ | |
| Gate Emitter Leakage Current | I_{GES} | nA | -500 | - | +500 | $V_{CE}=3,300\text{V}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$ | |
| Collector Emitter Saturation Voltage | V_{CEsat} | V | 2.5 | 2.85 | 3.5 | $I_C=1,800\text{A}, V_{GE}=15\text{V}, T_{vj}=150^\circ\text{C}$ | |
| Gate Emitter Threshold Voltage | $V_{GE(th)}$ | V | 5.5 | 6.5 | 7.5 | $V_{CE}=10\text{V}, I_C=1,800\text{mA}, T_{vj}=25^\circ\text{C}$ | |
| Input Capacitance | C_{ies} | nF | - | 132 | - | $V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_{vj}=25^\circ\text{C}$ | |
| Internal Gate Resistance | $R_{G(int)}$ | Ω | - | 1.3 | - | $V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_{vj}=25^\circ\text{C}$ | |
| Turn On Delay Time | $t_{d(on)}$ | μs | - | 0.8 | - | $V_{CC}=1,800\text{V}, I_C=1,800\text{A}$ | |
| Rise Time | t_r | | - | 0.3 | - | $L_S=100\text{nH}$ | |
| Turn Off Delay Time | $t_{d(off)}$ | | - | 2.2 | - | $R_G(\text{on/off})=4.7\Omega/5.6\Omega$ (3) | |
| Fall Time | t_f | | - | 1.8 | - | $V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$ | |
| Peak Forward Voltage Drop | V_F | V | 2.2 | 2.6 | 2.9 | $I_F=1,800\text{A}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$ | |
| Reverse Recovery Time | t_{rr} | μs | - | 0.7 | - | $V_{CC}=1,800\text{V}, I_F=1,800\text{A}, L_S=100\text{nH}$ $T_{vj}=150^\circ\text{C}$ | |
| Turn On Loss | E_{on} | J/P | - | 3.7 | - | $V_{CC}=1,800\text{V}, I_C=1,800\text{A}, L_S=100\text{nH}$ | |
| Turn Off Loss | E_{off} | J/P | - | 3.3 | - | $R_G(\text{on/off})=4.7\Omega/5.6\Omega$ (3) | |
| Reverse Recovery Loss | E_{rr} | J/P | - | 2.4 | - | $V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$ | |
| Short Circuit Pulse Width | t_{sc} | μs | 10 | - | - | $V_{CC}=2,000\text{V}, L_S=100\text{nH}$ $R_G(\text{on/off})=4.7/56\Omega, V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$ | |
| Stray inductance module | L_{SCE} | nH | - | 12 | - | | |
| Thermal Impedance | IGBT | $R_{th(j-c)}$ | K/W | - | - | 0.0075 | Junction to case |
| | FWD | $R_{th(f-c)}$ | | - | - | 0.0125 | |
| Contact Thermal Impedance | $R_{th(c-f)}$ | K/W | - | 0.005 | - | Case to fin | |

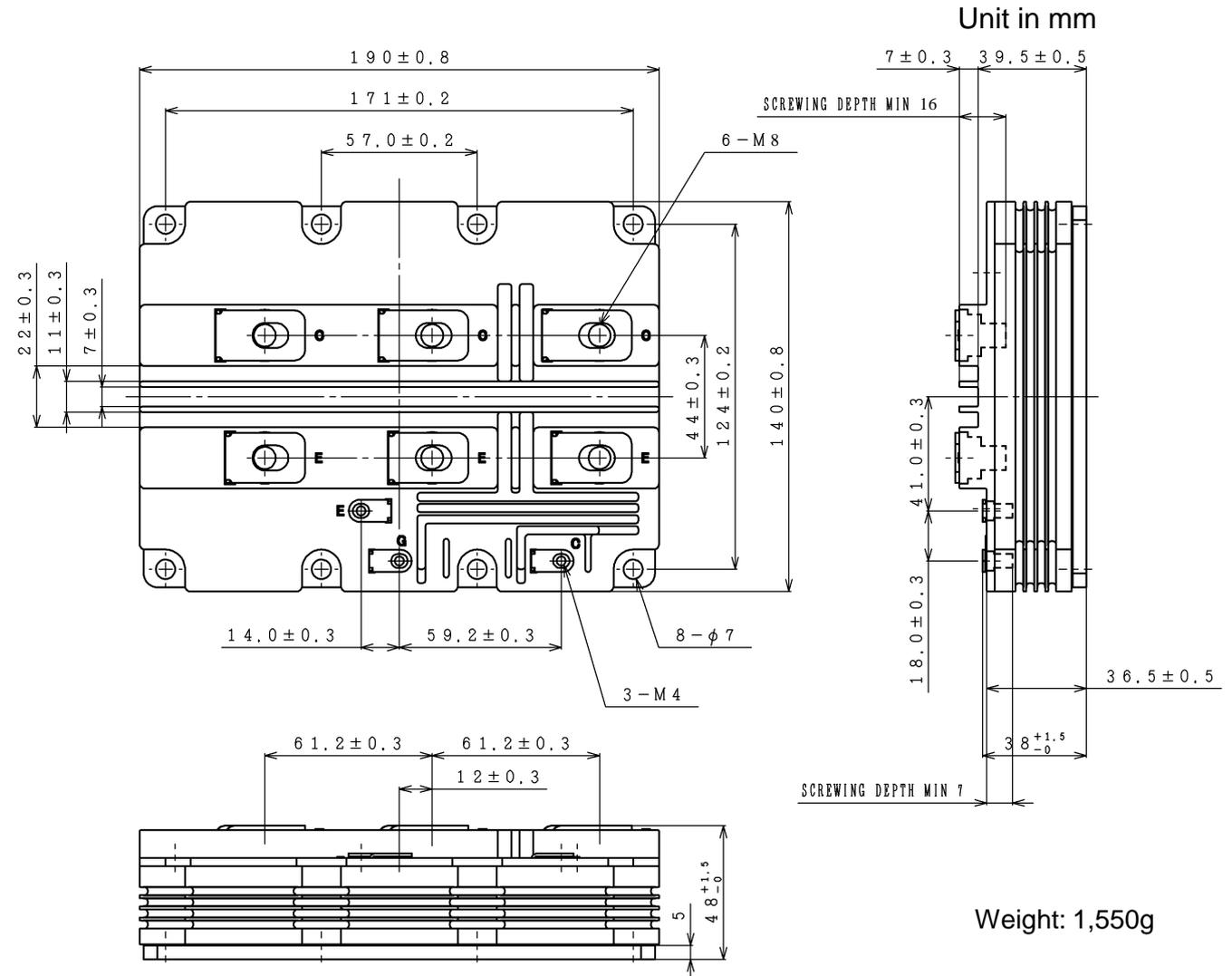
Notes: (3) R_G value is a test condition value for evaluation, not recommended value.

Please, determine the suitable R_G value by measuring switching behaviors.

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.
- * ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

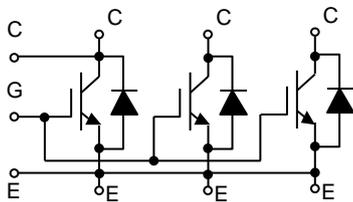
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OUTLINE DRAWING

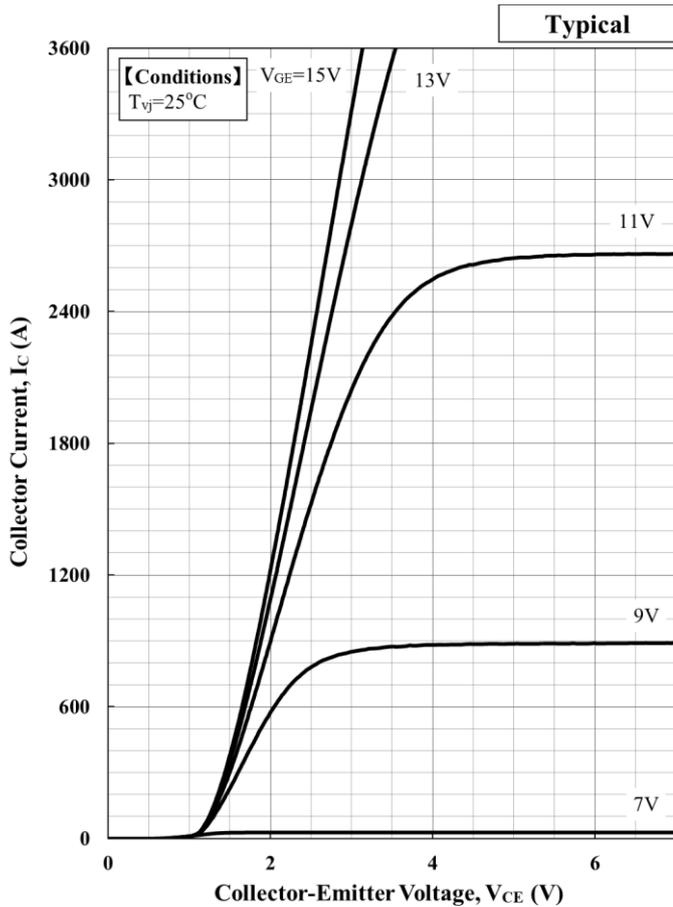


Weight: 1,550g

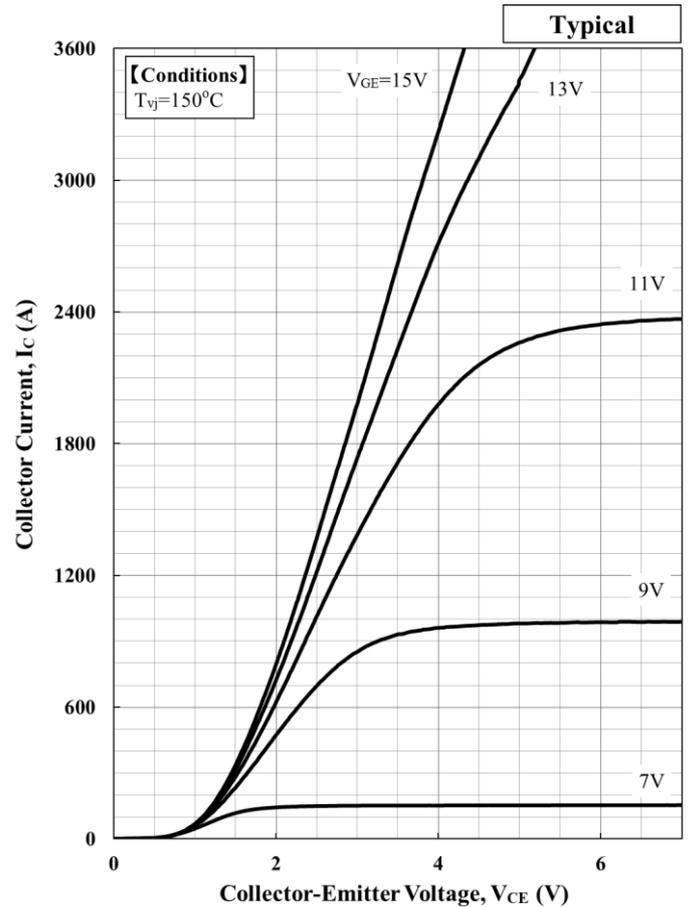
CIRCUIT DIAGRAM



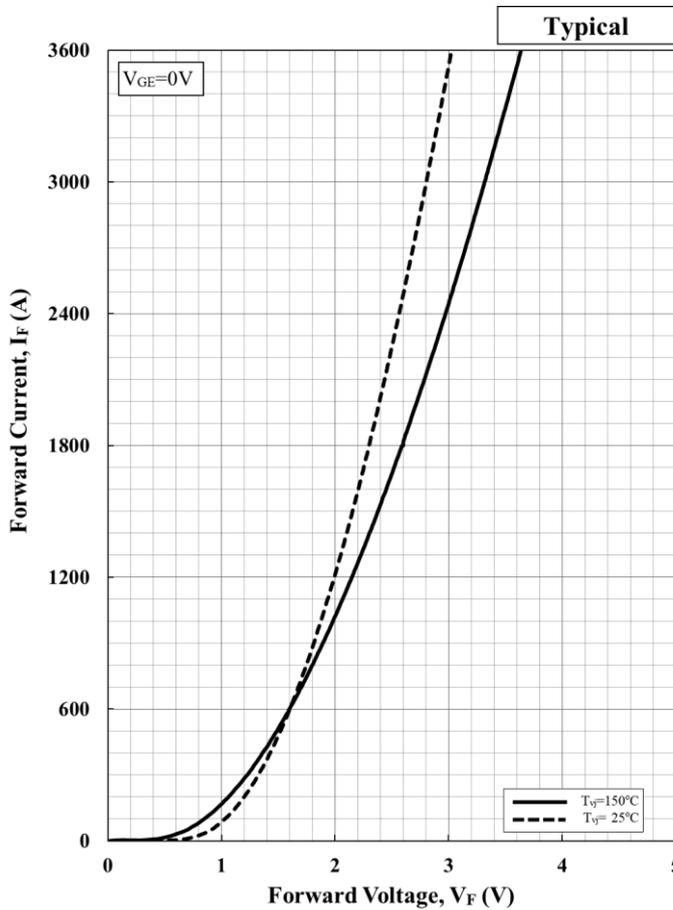
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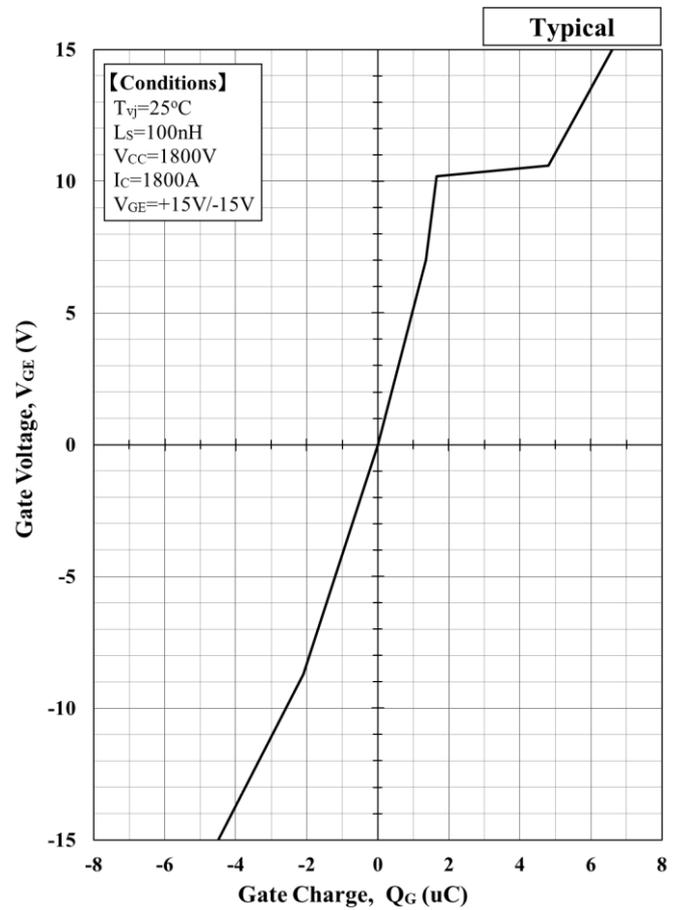
Collector Current vs. Collector Emitter Voltage



Collector Current vs. Collector Emitter Voltage

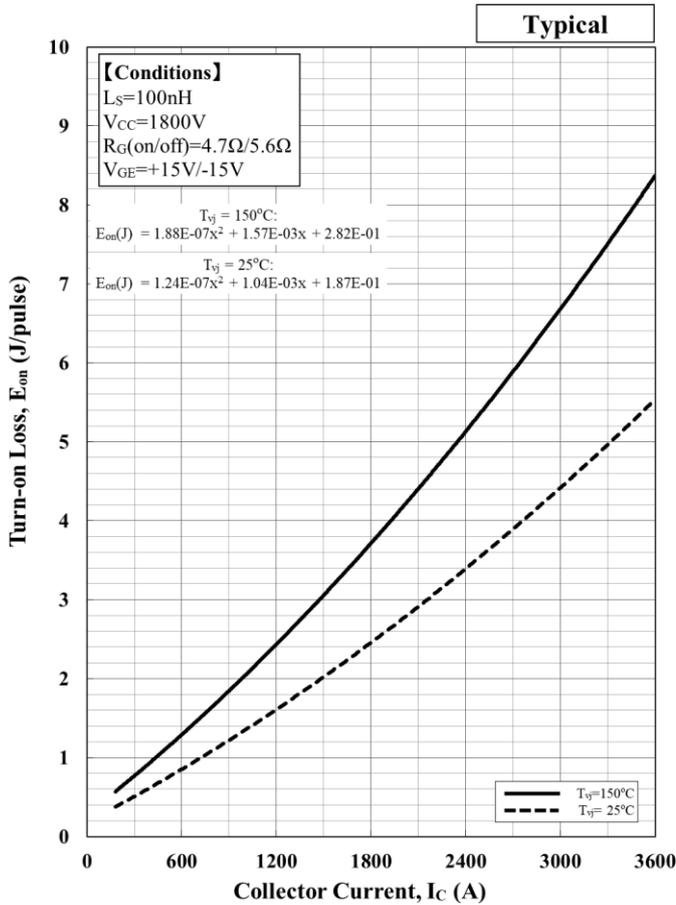


Forward Voltage of free-wheeling diode

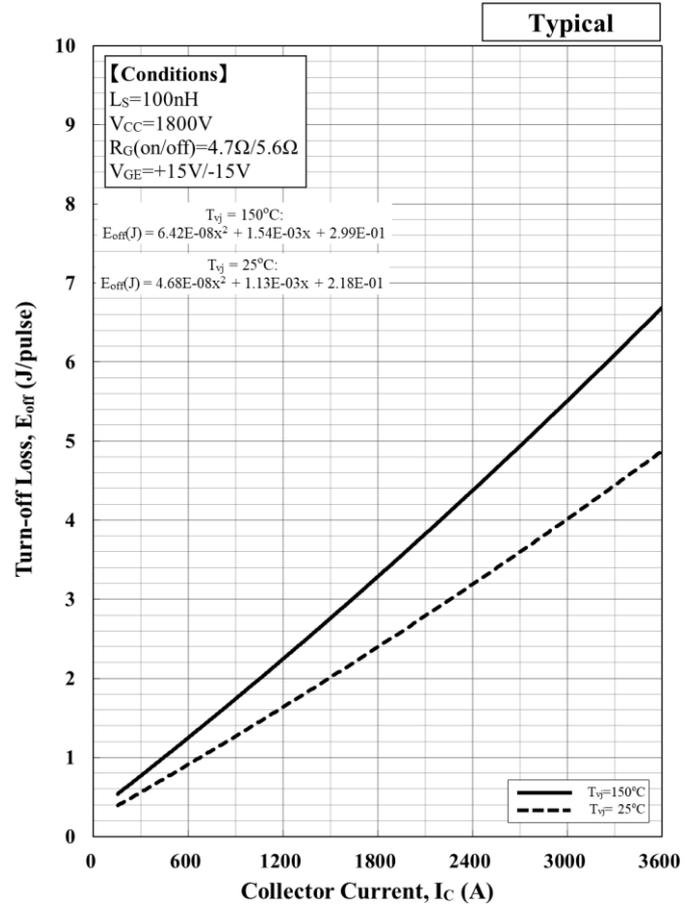


$V_{GE}-Q_G$ curve

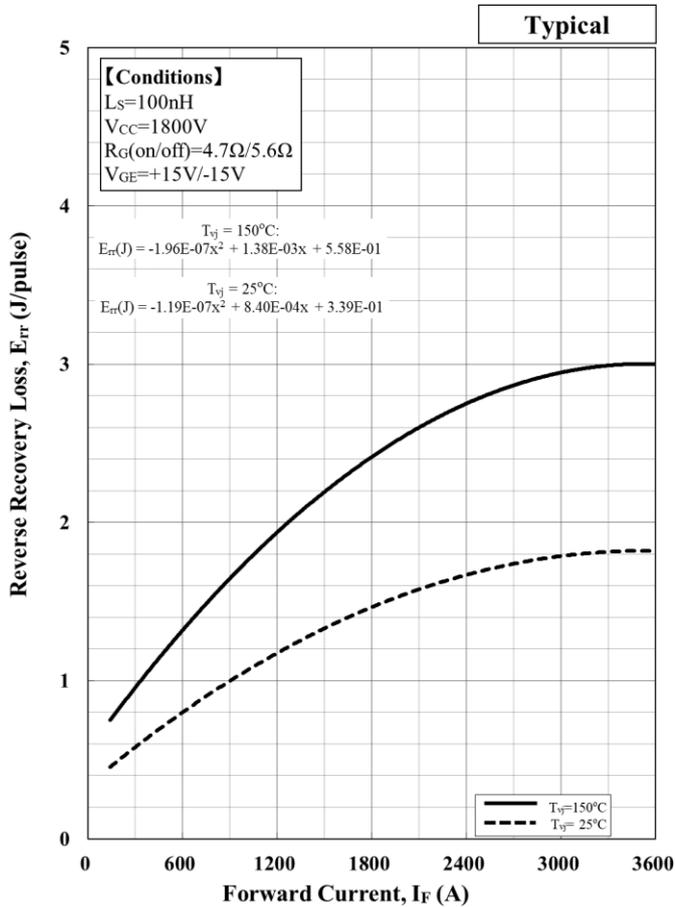
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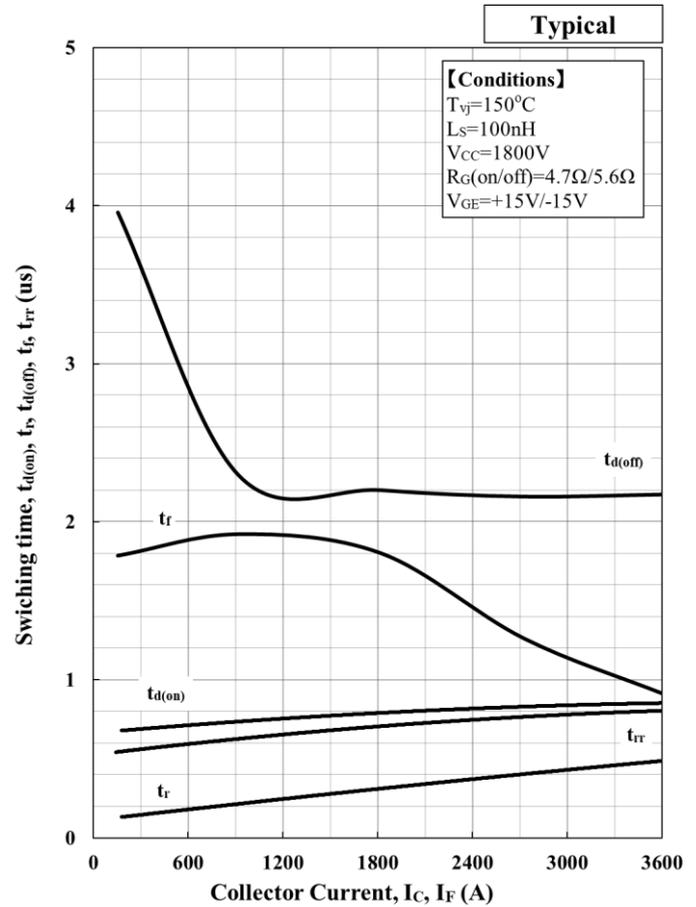
Turn-on loss vs. Collector current



Turn-off loss vs. Collector current

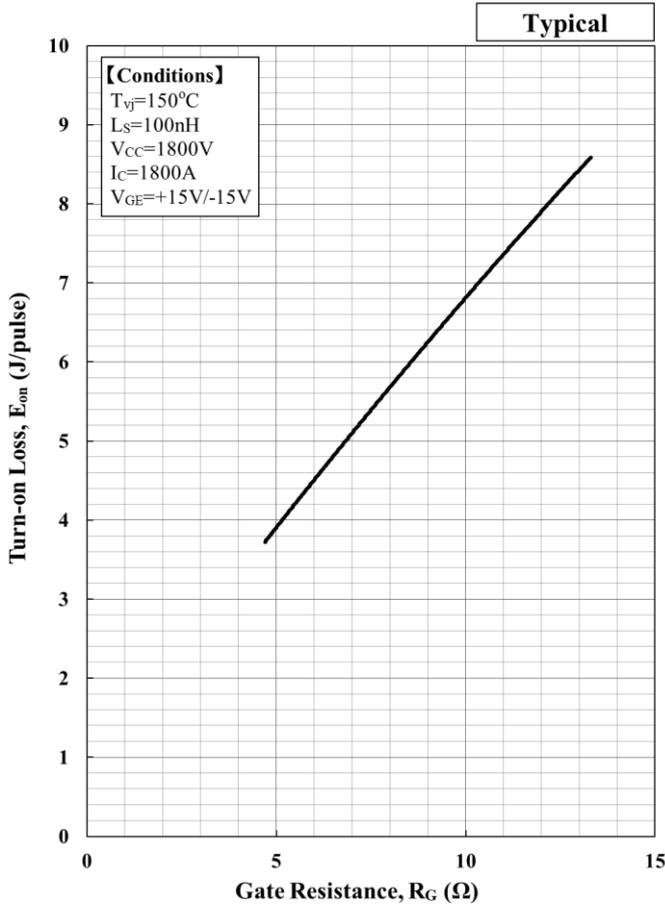


Recovery loss vs. Forward current

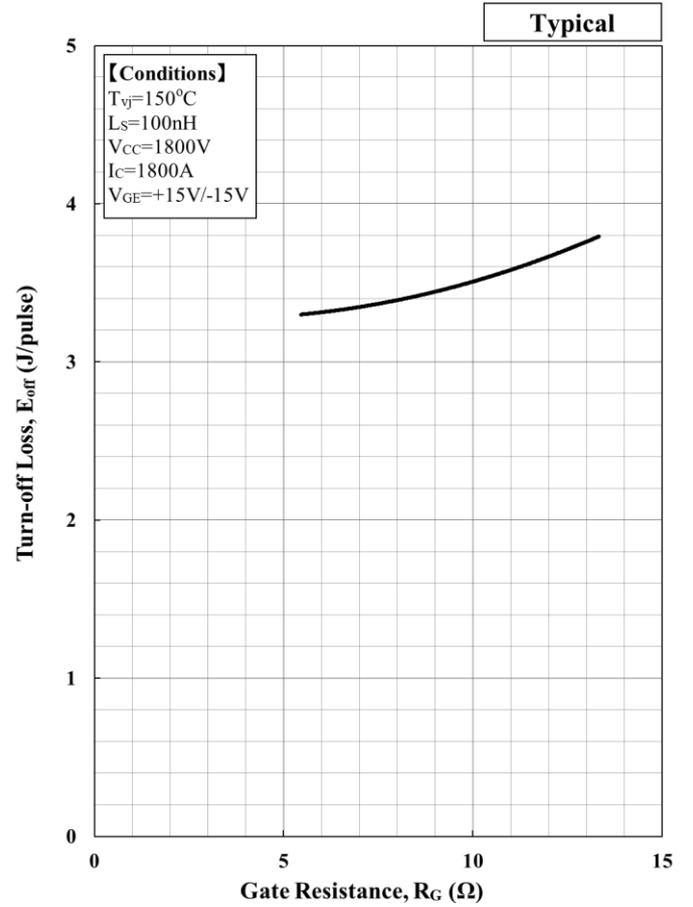


Switching time vs. Collector Current

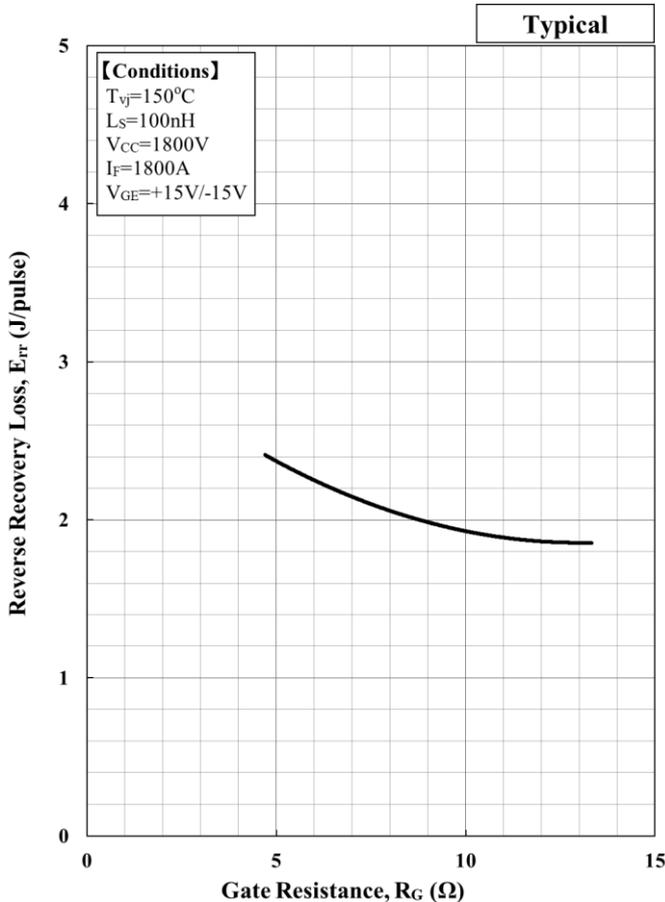
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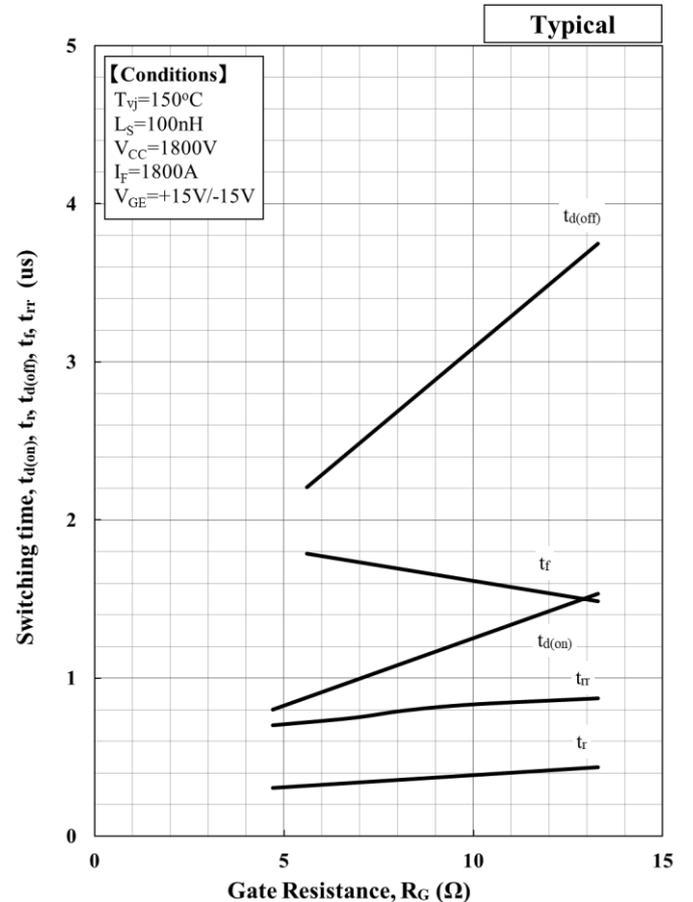
Turn-on loss vs. Gate Resistance



Turn-off loss vs. Gate Resistance

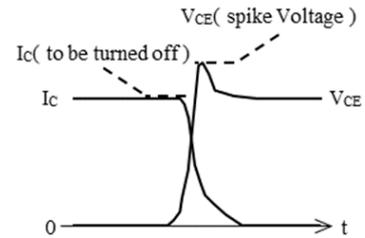
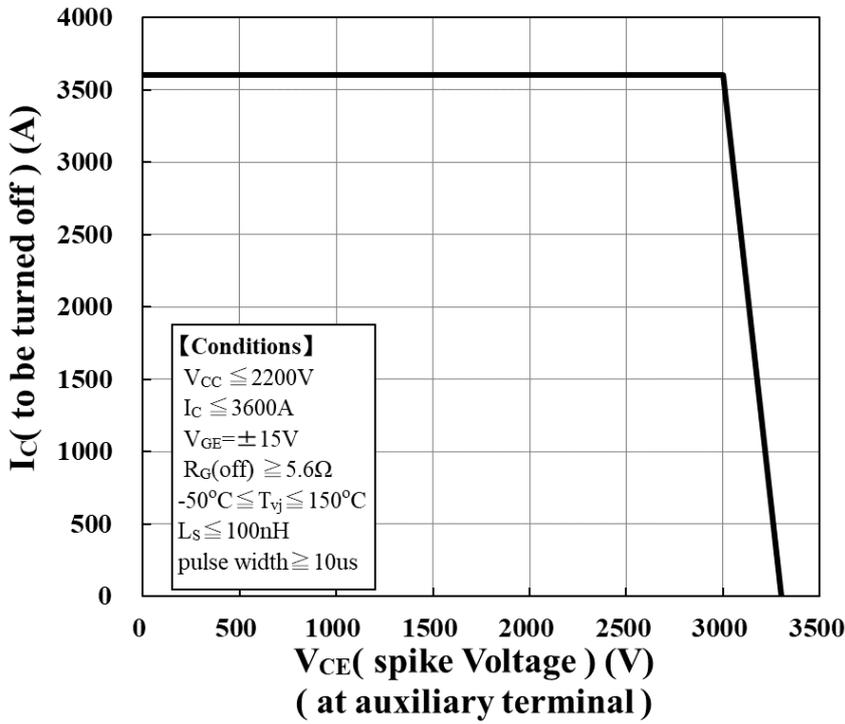


Recovery loss vs. Gate Resistance



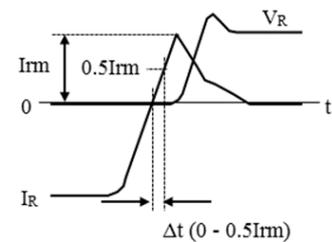
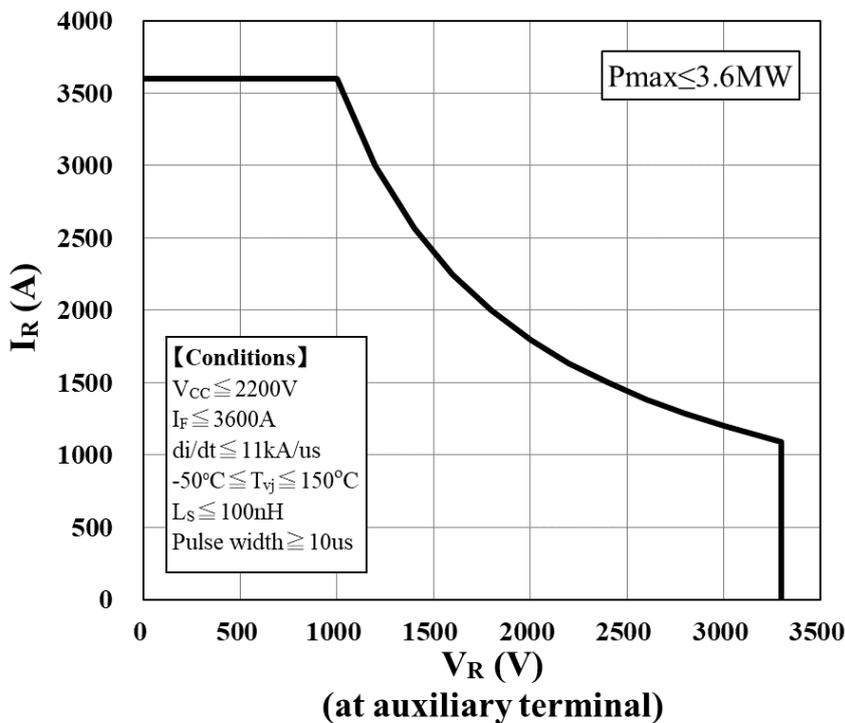
Switching time vs. Gate Resistance

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Definition of RBSOA waveform

Reverse Bias Safe Operation Area (RBSOA)

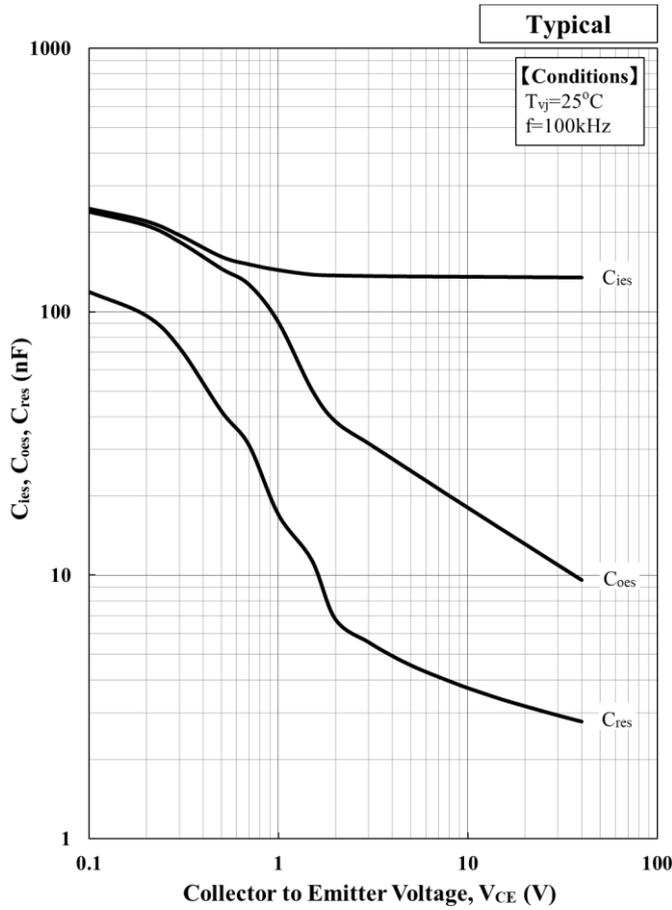


$$di/dt = \frac{0.5I_{rm}}{\Delta t}$$

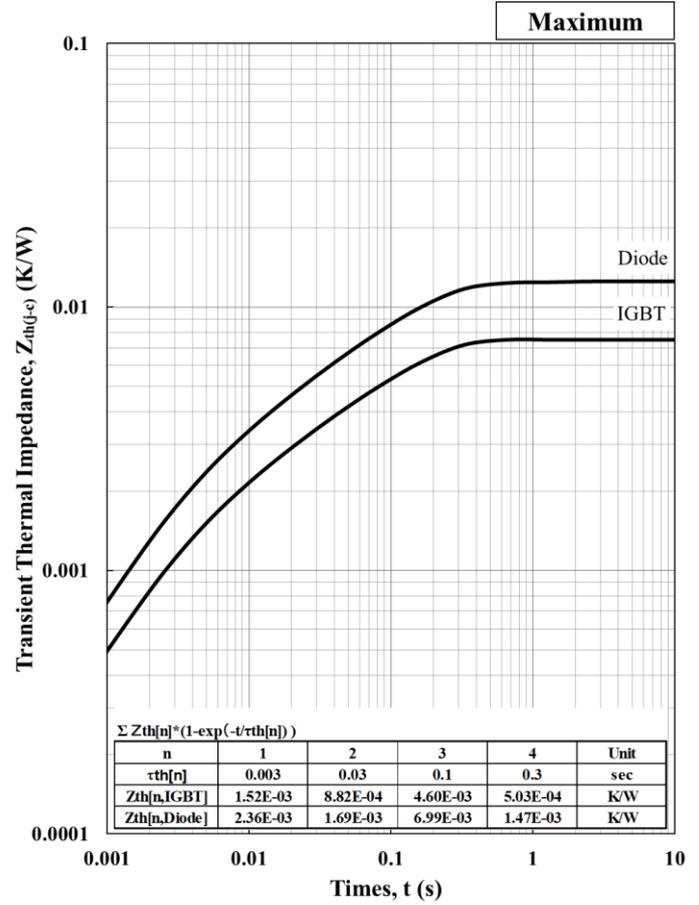
Definition of Recovery di/dt

Reverse Recovery Safe Operation Area (RRSOA)

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Capacitance vs. Collector to Emitter Voltage



Transient Thermal Impedance Curve

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HITACHI POWER SEMICONDUCTORS

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